

Application/Control No.	Applicant(s)/Patent under Reexamination	-
10/616,404	OSHIKAWA ET AL.	
Examiner	Art Unit	
Quana N. Vo	2625	

SEARCHED					
Class	Subclass	Date	Examiner		
358	1.9	4/16/2007	QV		
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INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
US Pat, US PG Pub, USOCR, EPO, JPO, DERWENT, IBM	4/16/2007	QV		
Inventor Name Search, see attachment	4/16/2007	QV		